

Date:

14-Oct-2022

**Product Category:** 

**USB Transceivers** 

**PCN Type:** 

# Product Change Notification / MFOL-04PKQY369

Manufacturing Change
Notification Subject:
CCB 4630.002 Final Notice: Qualification of STA as an additional assembly site for USB3340-EZK, USB3340-EZK-TR, USB3370B-EZK and USB3370B-EZK-TR catalog part numbers (CPN) available in 32L VQFN (5x5x0.9mm) package.
Affected CPNs:
MFOL-04PKQY369_Affected_CPN_10142022.pdf MFOL-04PKQY369_Affected_CPN_10142022.csv
Notification Text:
PCN Status:Final Notification
PCN Type:Manufacturing Change
Microchip Parts Affected: Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)
<b>Description of Change:</b> Qualification of STA as an additional assembly site for USB3340-EZK, USB3340-EZK-TR, USB3370B-EZK and USB3370B-EZK-TR catalog part numbers (CPN) available in 32L VQFN (5x5x0.9mm) package.

Page 1 of 3

#### **Pre and Post Change Summary:**

	Pre Change	Post	Change
Assembly Site	ASE Inc. (ASE)	ASE Inc. (ASE)	STATS Chippac Ltd. (STA)
Wire Material	CuPd	CuPd	CuPdAu
Die Attach Material	EN-4900F	EN-4900F	8290
Molding Compound Material	G631B	G631B	G700E
Lead-Frame Material	C194 C194		C194
Lead-Frame Paddle Size	138X138 mils	138X138 mils	138X138 mils
DAP Surface Prep	Double Ring Plating	Double Ring Plating	Ring Plating
·	See Pre and	Post Change Summary	y for comparison.

Impacts to Data Sheet:None

Change Impact:None

**Reason for Change:**To improve on-time delivery performance by qualifying STA as an additional assembly site.

**Change Implementation Status:**In Progress

Estimated First Ship Date: November 16, 2022 (date code: 2247)

Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

### **Time Table Summary:**

	October 2022				N	love	mbei	r <b>202</b>	2	
14/ 1	4	4	4	4	4	4	4	4	4	4
Workweek	0	1	2	3	4	5	6	7	8	9
Qual Report Availability		х								
Final PCN Issue Date		Х								
Estimated Implementation Date								х		

Method to Identify Change:Traceability code

**Qualification Report:**Please open the attachments included with this PCN labeled as PCN\_#\_Qual\_Report.

#### **Revision History:**

October 06, 2022: Issued final notification.

October 14, 2022: Re-issued final notification to remove the tray comparison drawing in pre and post change summary.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

#### **Attachments:**

PCN\_MFOL-04PKQY369 Pre and Post Change Summary.pdf PCN\_MFOL-04PKQY369\_Qual Report.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

#### **Terms and Conditions:**

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our <u>PCN</u> home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the <u>PCN FAO</u> section.

If you wish to <u>change your PCN profile</u>, <u>including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.



# QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

PCN ID#: MFOL-04PKQY369

Date: November 2, 2021

Qualification of STA as an additional assembly site for selected LAN9303, LAN9210 and LAN9211 device families available in 56L VQFN (8x8x0.9mm) package. The selected USB3340-EZK, USB3340-EZK-TR, USB3370B-EZK and USB3370B-EZK-TR catalog part numbers (CPN) available in 32L VQFN (5x5x0.9mm) package will qualify by similarity (QBS).



Purpose Qualification of STA as an additional assembly site for selected LAN9303, LAN9210

and LAN9211 device families available in 56L VQFN (8x8x0.9mm) package. The selected USB3340-EZK, USB3340-EZK-TR, USB3370B-EZK and USB3370B-EZK-TR catalog part numbers (CPN) available in 32L VQFN (5x5x0.9mm) package will

qualify by similarity (QBS).

**CCB** 4630.002 and 4630

**CN** ES361355

QUAL ID R2100817 REV. A
MP CODE TA3017RTXB0C
Part No. LAN9303I-ABZJ

Bonding No. BDM-002969 Rev. A

**Package** 

Type 56L VQFN

Package size 8 x 8 x 0.9 mm

**Lead Frame** 

Paddle size 236 x 236 mils

Material C194

Surface Double Ring

Process Etched

Lead Lock No

Part Number R002-3646X

Material

**Epoxy** 8290

Wire CuPdAu wire

Mold CompoundG700EPlating CompositionMatte Sn



## **Manufacturing Information**

Assembly Lot No.	Wafer Lot No.	Date Code
STA-221300006.000	TC11922050505.100	2125YMV
STA-221300008.000	TC11922050505.100	2125YPR
STA-221300007.000	TC11922050505.100	2125YPH

Result	Pass	Fail	
--------	------	------	--

56L VQFN (8x8x0.9 mm) assembled by STA pass reliability test per QCI-39000. This package was qualified the Moisture/Reflow Sensitivity Classification Level 3 at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT							
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks	
Precondition Prior Perform	Electrical Test: +25°C and 100°C System: EX_ANALOG	JESD22- A113	693(0)	693		Good Devices	
(At MSL Level 3)	Bake 150°C, 24 hrs System: CHINEE	JIP/ IPC/JEDEC		693			
	30°C/60%RH Moisture Soak 192 hrs. System: TABAI ESPEC Model PR-3SPH	J-STD-020E		693			
	3x Convection-Reflow 265°C max			693			
	System: Vitronics Soltec MR1243  Electrical Test: +25°C and 100°C  System: EX_ANALOG			0/693	Pass		

	PACKAGE QUALIF	FICATION	IREP	ORT		
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Electrical Test: +100°C System: EX_ANALOG	JESD22- A104	231(0)	231 0/231	Pass	Parts had been pre-conditioned at 260°C 77 units / lot
Temp Cycle	Stress Condition: -65°C to +150°C, 1000 Cycles System: TABAI ESPEC TSA-70H			231		
	Electrical Test: +100°C System: EX_ANALOG		231(0)	0/231	Pass	
	Bond Strength: Wire Pull (> 2.50 grams) Bond Shear (>12.60 grams)		15 (0) 15 (0)	0/15 0/15	Pass Pass	
	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X	JESD22- A118		231		Parts had been pre-conditioned at 260°C
	Electrical Test: +25°C System: EX_ANALOG		231(0)	0/231	Pass	77 units / lot
UNBIASED- HAST	Stress Condition: +130°C/85%RH, 192 hrs. System: HAST 6000X			231		
	Electrical Test: +25°C System: EX_ANALOG		231(0)	0/231	Pass	

	PACKAGE QUALIFIC	ATION	NREF	PORT	•	
Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: SHEL LAB	JESD22- A103		45		45 units
	Electrical Test: +25°C and 100°C System: EX_ANALOG		45(0)	0/45	Pass	
Solderability	Steam Aging: Temp 93°C,8Hrs System: SAS-3000	J-STD-002	22 (0)	22		
Temp 245°C	Solder Dipping:Solder Temp.245°C Solder material:Pb Free Sn 95.5Ag3.9 Cu0.6 System: ERSA RA 2200D Visual Inspection: External Visual Inspection			0/22	Pass	
Physical	Physical Dimension,	JESD22- B100/B108	30(0) Units	0/30	Pass	
Dimensions	10 units from 1 lot	5100/6100	UIIIIS			
Bond Strength	Wire Pull (> 3.00 grams)	Mil. Std. 883-2011	30 (0) Wires	0/30	Pass	
Data Assembly	Bond Shear (> 8.00 grams)	CDF-AEC- Q100-001	30 (0) bonds	0/30	Pass	

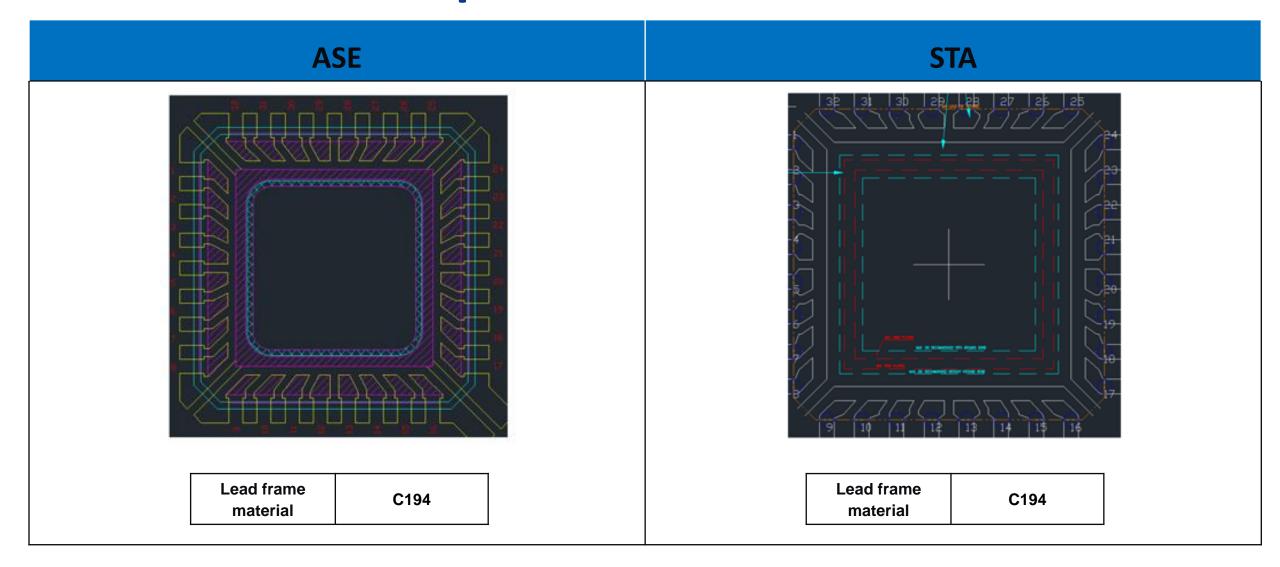
# CCB 4630.002 Pre and Post Change Summary PCN# MFOL-04PKQY369



A Leading Provider of Smart, Connected and Secure Embedded Control Solutions



# **Lead Frame Comparison**





MFOL-04PKQY369 - CCB 46 USB3340-E USB3370B-EZK and USB3370B-EZK-TR catalog part numbers (CPN) av

Affected Catalog Part Numbers(CPN)

USB3340-EZK USB3340-EZK-TR USB3370B-EZK USB3370B-EZK-TR